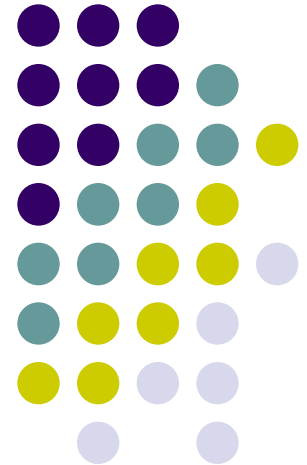


Meeting the Challenges of Testing Filtered Connectors

Brian.J.Frost CEng MIET
Managing Director
Applied Relay Testing Ltd, England



www.appliedrelaytesting.co.uk



Filtered connectors – increasingly important.

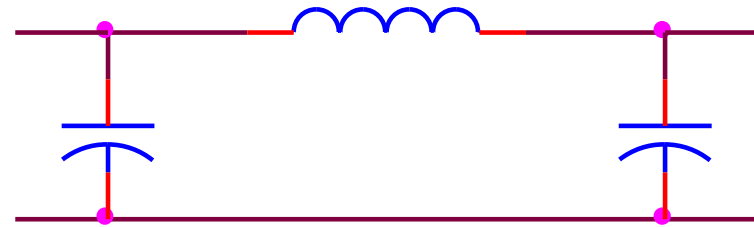


- A filtered connector is any type of connector that contains additional components to attenuate the passage of unwanted signals through it.
- Increasingly used to protect ‘mission critical’ electronic systems against EMI such as lightning discharges and unwanted RF transmissions - inward or outward!
- Market sector likely to increase further as use of composite housing or airframe materials increases.
- Filtered connectors are an example of a ‘complex passive’ – apparently simple to test yet requiring careful attention to test solutions. Correct testing of these parts is not trivial.
- A solution is presented for meeting and exceeding these test challenges.

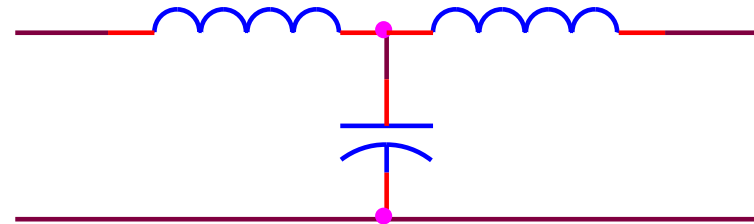
A typical filtered connector internal circuit.



- Two main types of filter exist – 'Pi' and 'T'.
- The common connection may be the shell of the connector or common to one of several logical groups (e.g. a data bus).
- Pins may also contain over-voltage protection devices such as zeners or varistors connected in various configurations.



'Pi' Filter



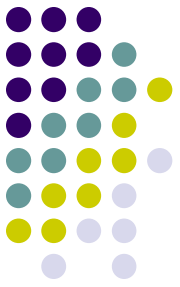
'T' Filter

Physical construction is becoming more integrated.



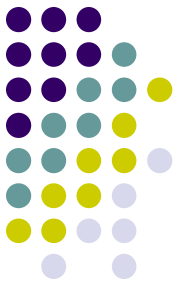
- Early filtered connectors were made using PCB-mounted discrete components – difficult to assemble and less reliable in use.
- Capacitor arrays improved integration and filter performance.
- Combination of capacitor and varistor array is the most highly integrated.

The need for a dedicated filter connector test system.



- The basic tests are simple - Capacitance, IR and DWV - relatively easy to measure with discrete equipment - BUT..
- Need to measure these same parameters over many test routes.
- Measurements are required between pins of the filtered connector in many different ways.
- Capacitance must be measured accurately to ensure valid construction and filter performance.
- Test connection to the device can introduce measurement errors.
- Use of a standard cable test system can seem attractive but parametric measurement quality is usually insufficient.

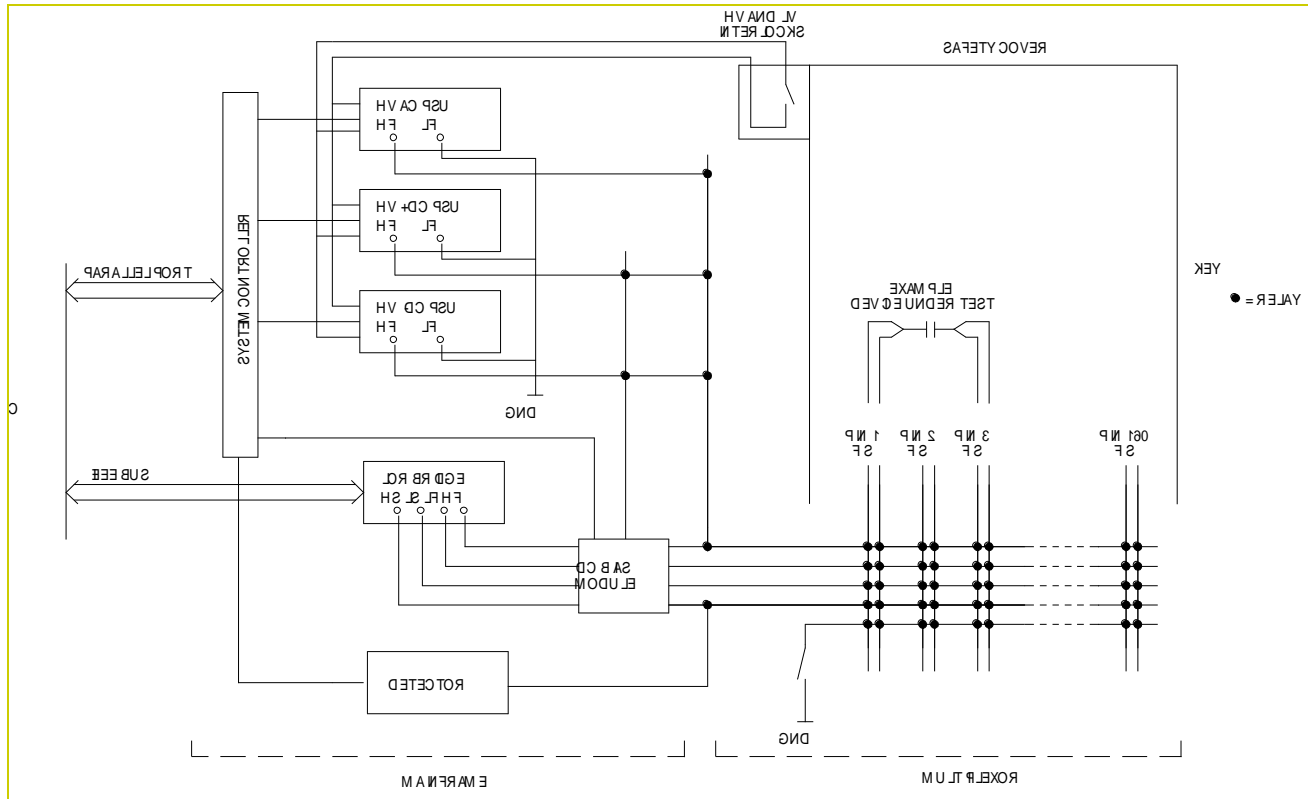
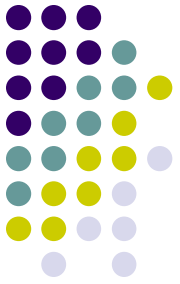
The Reflex 950 – a dedicated filter connector test system.



- Has up to 160 4-wire device connections.
- Test voltage up to 2100V peak, DC or 50-400Hz AC.
- Measures Cap and DF using LCR meter (e.g. Agilent) at elevated voltage.
- Measures insulation resistance (leakage current).
- Measures DWV (breakdown) using pulse capture and level.
- Measures through pin resistance (milliohms)
- Measures clamp voltage (zener, varistor).

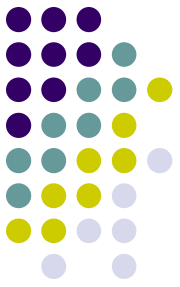


Tester electrical architecture.

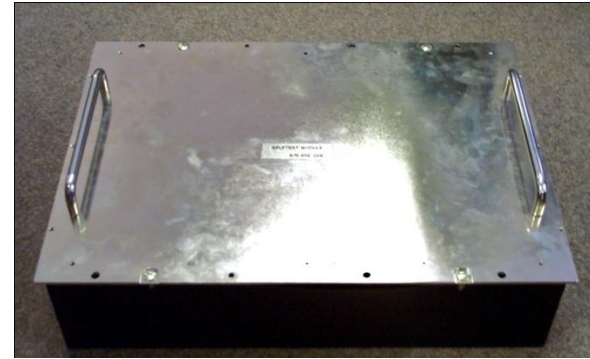


- Flexible 4-wire matrix connects the measure resources and the device under test.

Fixturing is vital for measurement performance.



- Filtered connector test device is mounted on a removable fixture module.
- Underside of fixture module is populated with pairs of connection 'lands' which mate with tester probe 'nails'.
- Wiring from these 'lands' to the device is internal to the module and easily customised.
- Solution provides very low stray capacitance and ease of device interchange.

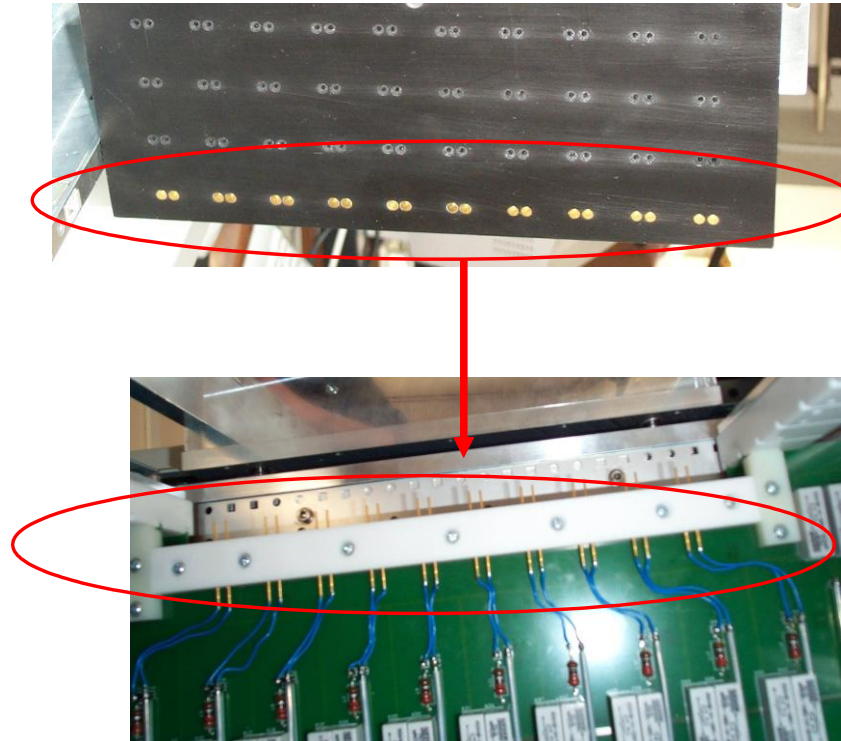


Fixturing is vital for measurement performance.



- Tester 'bed of nails' mates with the fixture module.
- A large test area provides opportunity to test one large connector or multiple smaller connectors.

Fixturing is vital for measurement performance.



- Device site connects almost directly to the switching network.

Fixturing is vital for measurement performance.



- Close physical connection of the device site and the switching network.
- Stray capacitance and crosstalk dramatically reduced over a cable solution.



Test execution – visual techniques aid clarity.



Reflex950 software, V1.0.41.264 (Administrator)

Home page **Offline**

Stop

Open

Release fixture

Busy

Tested 1
Passed 0 0.0%
Failed 0 0.0%

Part number --

Test sequence	
✓ 0 Batch definition	Test program
1 Hipot check	Route 2 of 30
2 Manual prompt	-----
3 Leakage current and IR	-----
4 Manual prompt 2	-----
5 Hipot check pin to pin	-----
6 Hipot check (2)	-----

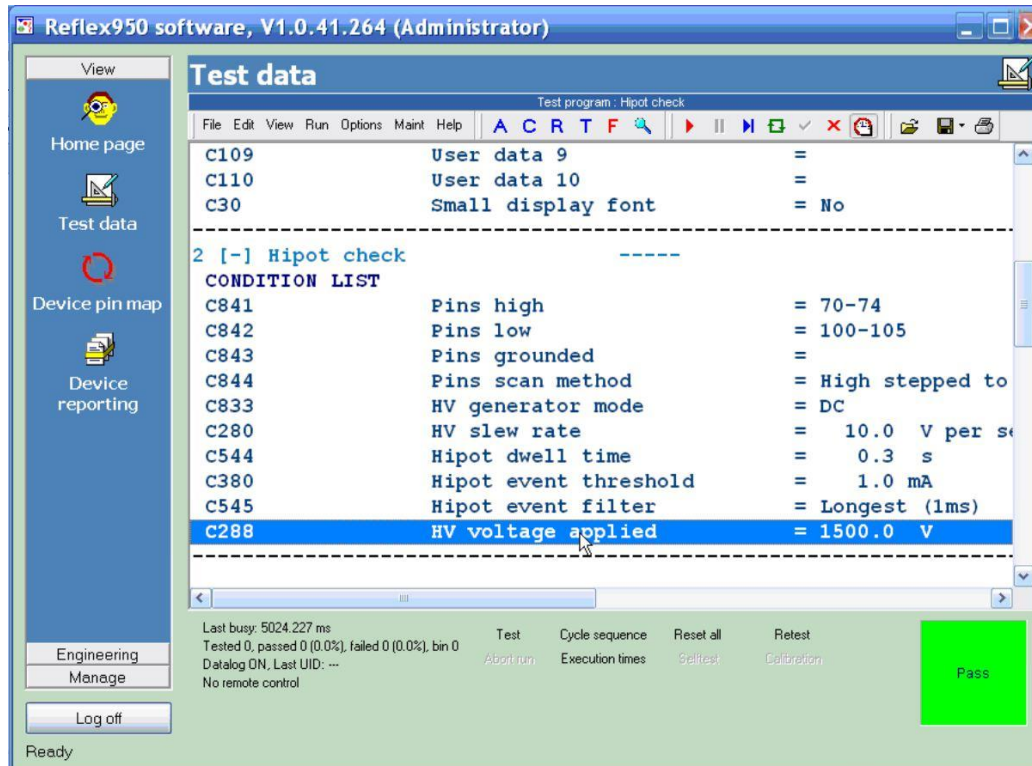
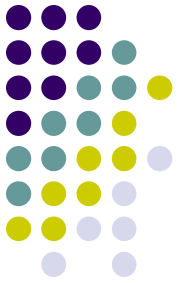
Engineering Manage

Log off

Hipot, Route 3 of 30

- Test activity and connections are displayed during test.
- Any test failure can be left visible for clarity.

Test programming

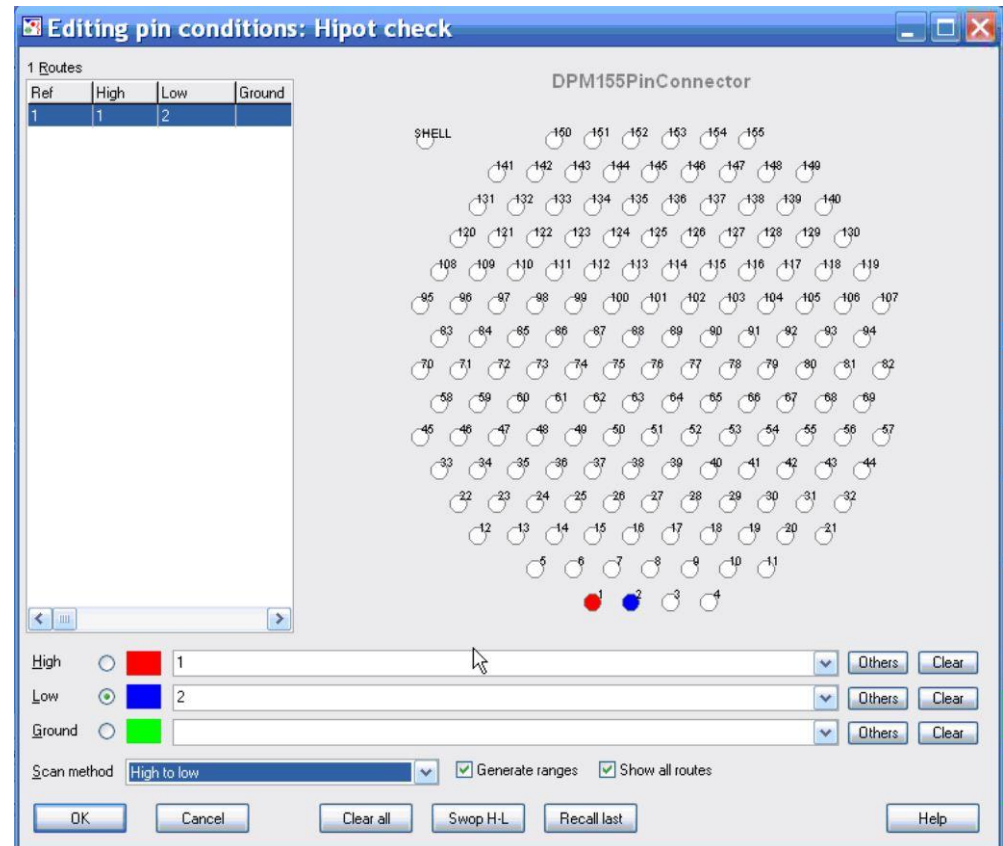


- Test programming uses a 'menu' structure for setting parameters.

Flexible pin connection editor.



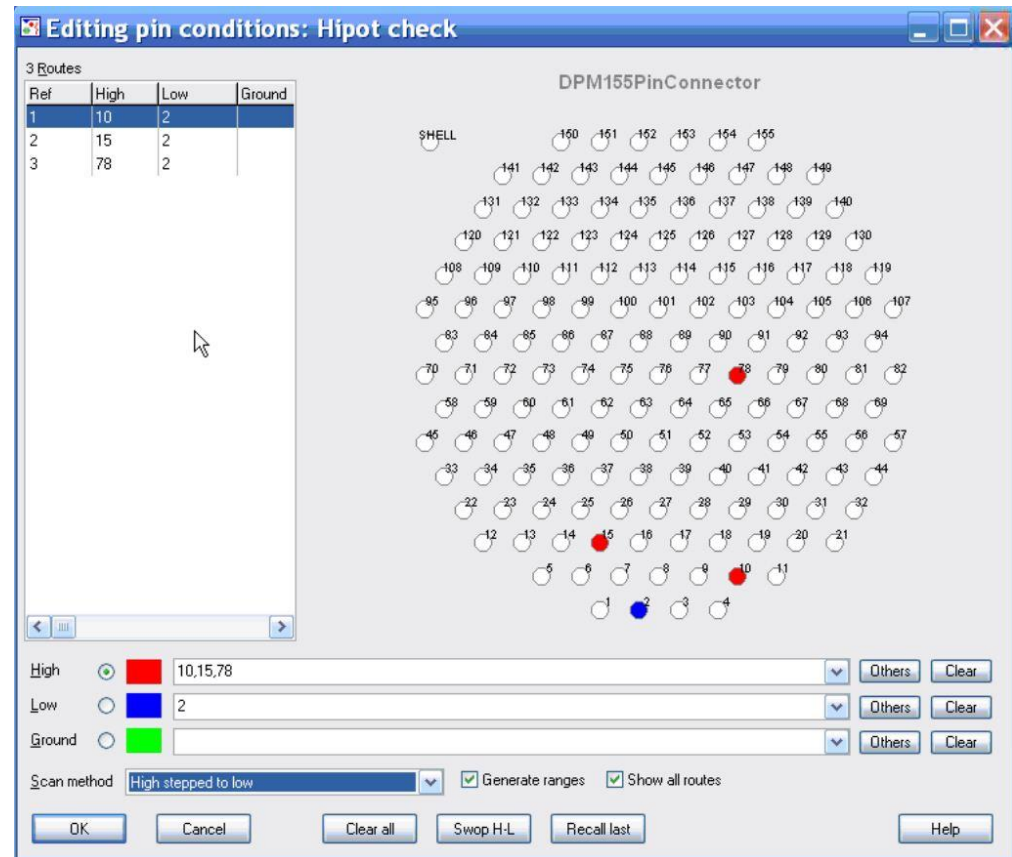
- Architecture maps 4-wire measurement bus on to any number of physical device connections.
- Working layout can be any chosen 'view', e.g. actual connector plan form or a derivative.



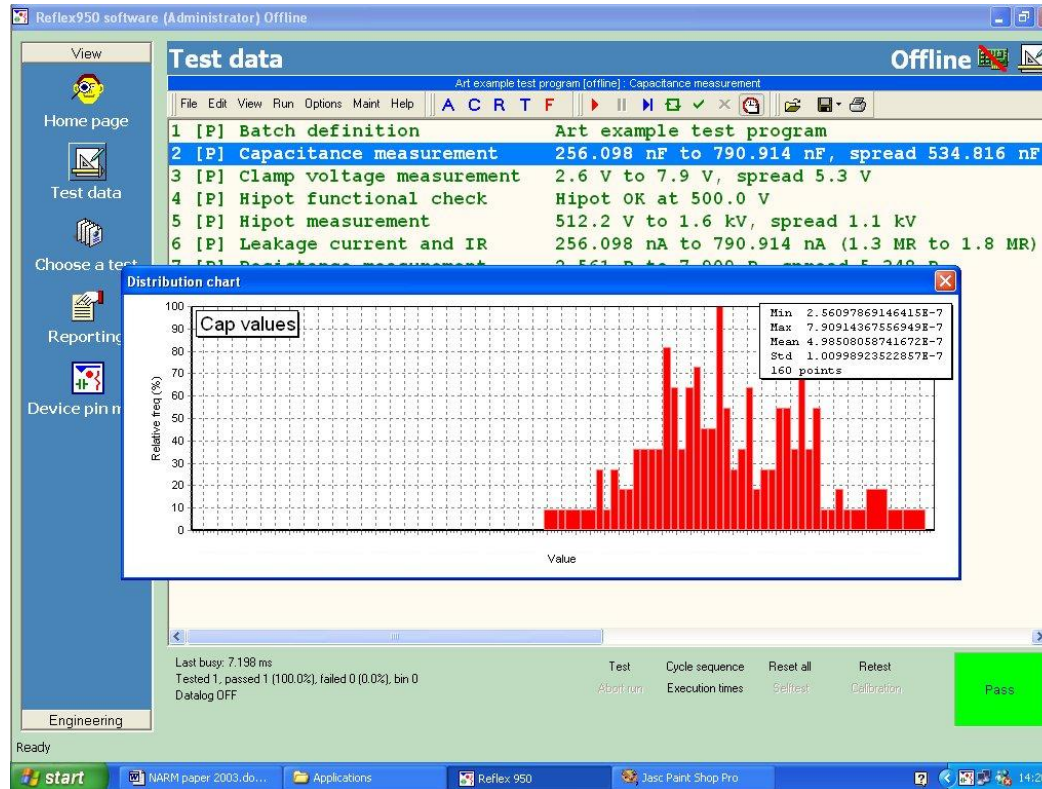


Flexible pin connection editor.

- Architecture maps 4-wire measurement bus on to any number of physical device connections.
- Working layout can be any chosen 'view', e.g. actual connector plan form or a derivative.
- All similar test routes are visible on one simple screen.

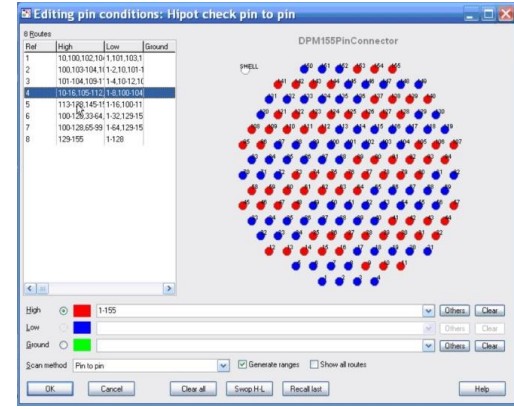
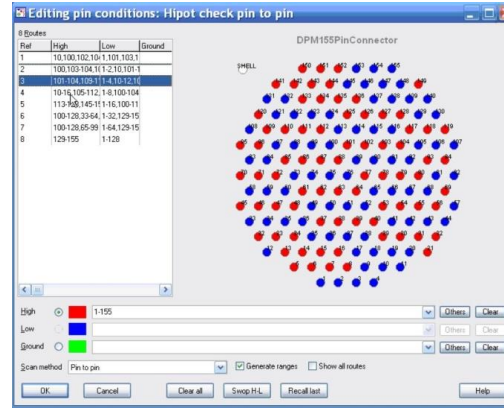
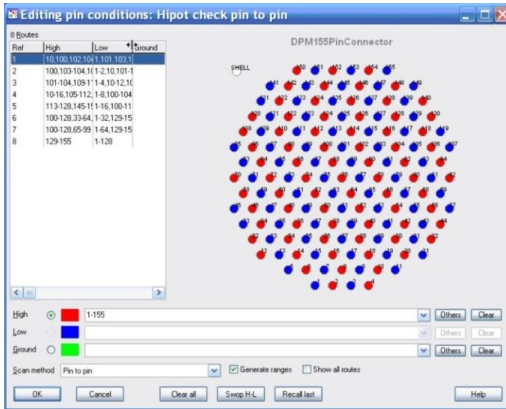


Charts are used to enhance result clarity.



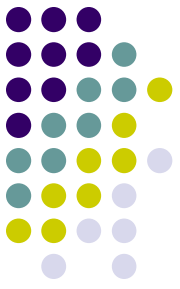
- Charts allow large number of routes to be compared, e.g. for assessing capacitance matching.

Pin-to-pin test method for fast device test coverage.



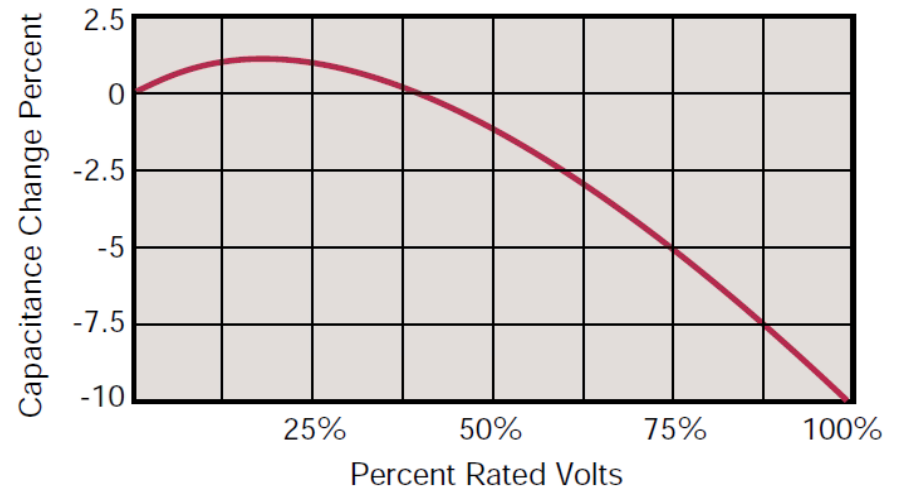
- 'Binary-split' technique is available for applying any test across a large number of pin connection routes.
- Guarantees test polarity reversal to all adjacent pins (e.g to confirm absence of solder 'whiskers' between pins).
- Technique permits 128-pin connector to be fully tested in only 7 automatic test steps.

Measuring capacitance at elevated voltage.



- Few designers using ceramic capacitors realise that capacitance can fall significantly with rising voltage.
- Capacitance change affects filter cut-off frequency and / or decoupling performance
- Filter connectors should be tested for this parameter.
- Most industry solutions only allow capacitance to be measured with a few tens of applied volts.

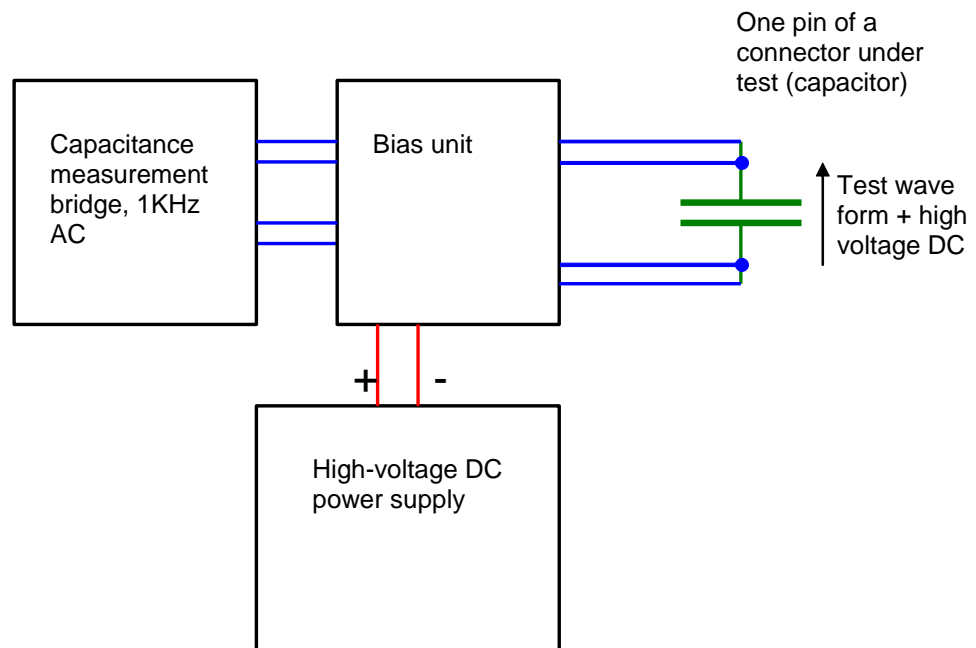
Typical Cap. Change vs. D.C. Volts
X7R



Measuring capacitance at elevated voltage.



- The Reflex 950 solution allows the entire applied voltage range to be used for capacitance and DF measurement.
- Full 4-wire isolation is achieved.



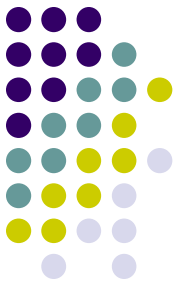
Measuring capacitance at elevated voltage.



- Valuable engineering insight is gained from elevated voltage capacitance measurement.
- The technique is increasingly popular and enhances customer confidence in quality.
- Technique is also applicable to a stand-alone laboratory application.



To conclude.



- Filtered connectors are increasingly important ‘complex passive’ devices.
- Correct testing of these unique parts is not trivial.
- A dedicated filtered connector test system has been created which implements novel fixturing, connection and test techniques to solve the test problems raised.
- Further test insight has been provided with the capability to measure Capacitance and DF at elevated voltage.

Thank You.